

STP9NK90ZFP-VB Datasheet

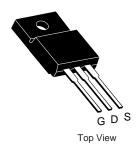
N-Channel 900 V (D-S) Super Junction Power MOSFET

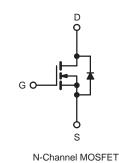
PRODUCT SUMMARY					
V _{DS} (V)	900				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	0.95			
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Single				

TO-220 FULLPAK

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted) PARAMETER SYMBOL LIMIT UNIT Drain-Source Voltage V_{DS} 900 V Gate-Source Voltage ± 20 V_{GS} T_C = 25 °C 7.0 V_{GS} at 10 V Continuous Drain Current I_D T_C = 100 °C А 5.5 Pulsed Drain Currenta 21 I_{DM} W/°C Linear Derating Factor 1.5 770 Single Pulse Avalanche Energy^b E_{AS} mJ Repetitive Avalanche Current^a 7.8 А I_{AR} Repetitive Avalanche Energy^a 19 mJ E_{AR} T_C = 25 °C Maximum Power Dissipation 65 W P_{D} Peak Diode Recovery dV/dtc 2.0 dV/dt V/ns Operating Junction and Storage Temperature Range T_J, T_{stg} - 55 to + 150 °C Soldering Recommendations (Peak Temperature) for 10 s 300d 10 lbf · in Mounting Torque 6-32 or M3 screw 1.1 N·m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/µs, V_{DD} \leq 600 V, T_J \leq 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



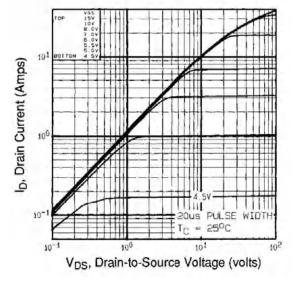
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THERMAL RESISTANCE RATI	NGS								
PARAMETER	SYMBOL	TYP.		MAX.		UNIT			
Maximum Junction-to-Ambient	R _{thJA}	-		40					
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24				°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.65							
		. N							
SPECIFICATIONS ($T_J = 25 \text{ °C}, u$		1			-	r	1	ł	
PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT	
Static		1				1	1	1	
Drain-Source Breakdown Voltage	V _{DS}		= 0 V, I _D = 2	-	900	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		e to 25 °C,		-	0.98	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}		= V_{GS} , I_D =		2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20 V$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =	= 900 V, V _G	_{is} = 0 V	-	-	100	μA	
	-255	-		/, T _J = 125 °C	-	-	500	μ.,	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	۱ _D	₀ = 5.6 A ^b		0.95	-	Ω	
Forward Transconductance	g fs	$V_{DS} =$	= 100 V, I _D =	= 5.6 A ^b	5.6	-	-	S	
Dynamic									
Input Capacitance	C _{iss}		V _{GS} = 0 V	,	-	3100	-		
Output Capacitance	C _{oss}	V _{DS} = 25 V,		-	800	-	pF		
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, se	e fig. 5	-	490	-		
Total Gate Charge	Qg				-	-	200	nC	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		A, V _{DS} = 400 V, ig. 6 and 13 ^b	-	-	24		
Gate-Drain Charge	Q _{gd}		0001		-	-	110		
Turn-On Delay Time	t _{d(on)}				-	19	-		
Rise Time	t _r	V _{DD} = 400 V, I _D = 5.6 A,		-	38	-	1		
Turn-Off Delay Time	t _{d(off)}	R _g =	= 6.2 Ω, R _D = see fig. 10	= 52 Ω ^{1b}	-	120	-	ns	
Fall Time	t _f	see lig. 10 ²		-	39	-	1		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH		
Internal Source Inductance	L _S			-	13	-			
Drain-Source Body Diode Characteristic	s	·							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	A		
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21			
Body Diode Voltage	V _{SD}	$T_J = 25 \text{ °C}, I_S = 5.6 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V		
Body Diode Reverse Recovery Time	t _{rr}	T.=	25 °C, I _F =	5.6 A.	-	650	980	ns	
Body Diode Reverse Recovery Charge	Q _{rr}		/dt = 100 A		-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time	is nealiaible (turn	-on is do	n is dominated by L_S and L_D)			

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



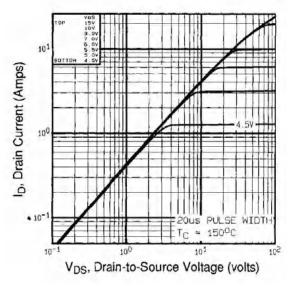


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

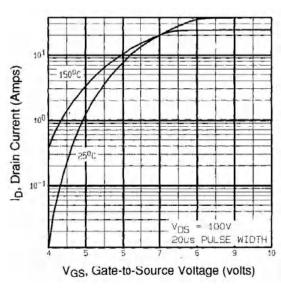
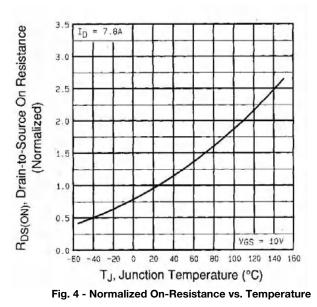


Fig. 3 - Typical Transfer Characteristics





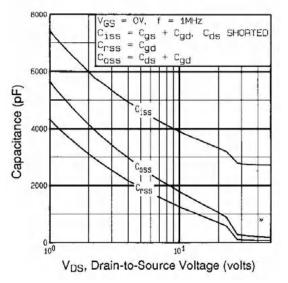


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

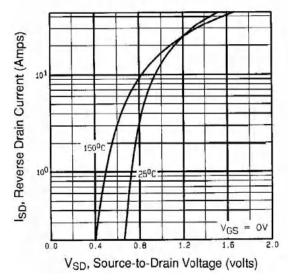


Fig. 7 - Typical Source-Drain Diode Forward Voltage

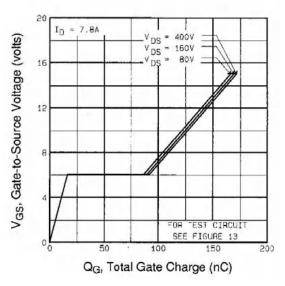
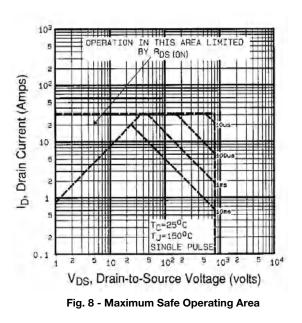


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





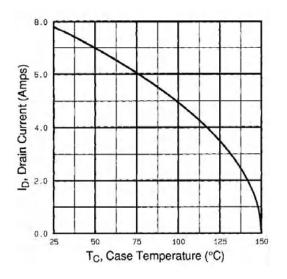


Fig. 9 - Maximum Drain Current vs. Case Temperature

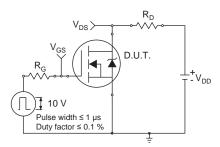


Fig. 10a - Switching Time Test Circuit

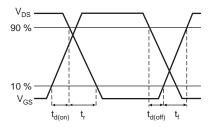


Fig. 10b - Switching Time Waveforms

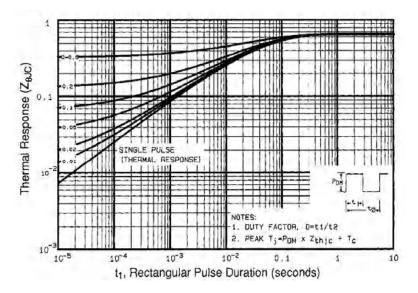


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



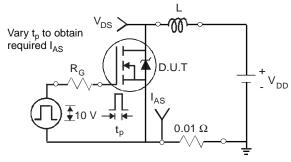


Fig. 12a - Unclamped Inductive Test Circuit

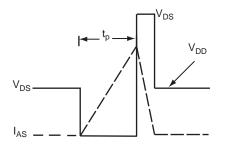


Fig. 12b - Unclamped Inductive Waveforms

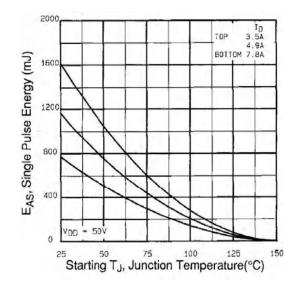


Fig. 12c - Maximum Avalanche Energy vs. Drain Current



Fig. 13a - Basic Gate Charge Waveform

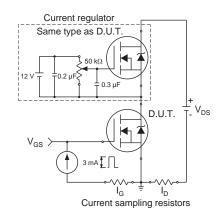
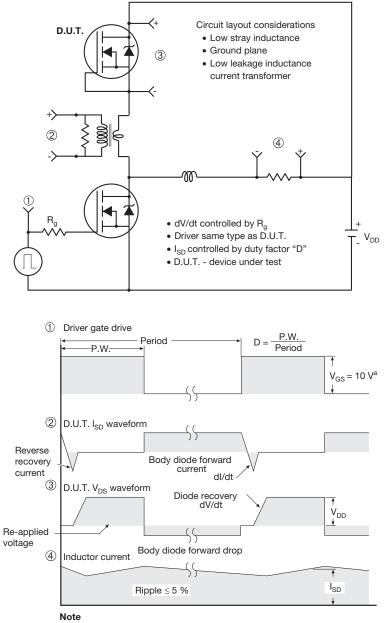


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

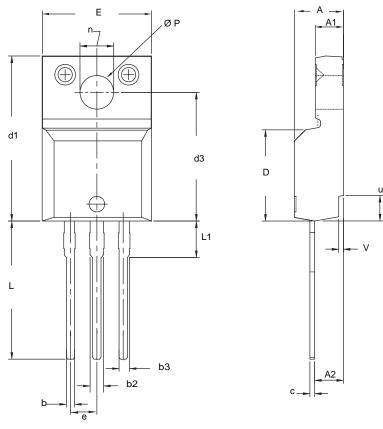


a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLI	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
C	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54 BSC		0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØP	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness.

5. No chipping or package damage.



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